

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10671548	MURAKAWA, AKIRA
	Examiner	Art Unit
	Nguyen, Khoi	2132

SEARCHED

Class	Subclass	Date	Examiner
713	156, 173	9/24/2008	JKG

SEARCH NOTES

Search Notes	Date	Examiner
EAST - USPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	9/24/2008	JKG
PALM - Inventor Name Search	9/24/2008	JKG

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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